

**Search Notes**

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Examiner

Nhan T. Tran

Applicant(s)/Patent under  
Reexamination

TANAKA, TOSHIYUKI

Art Unit

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**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
UPDATED EAST SEARCH (USPAT, PGPUB, JPO, EPO, DERWENT, IBM_TDB) test search - see search history printout	1/9/2006	NT
348/362-367, 220.1-221.1, 227.1-229.1 (test search - see search history printout)	1/9/2006	NT